

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination NOMURA ET AL.	
		Examiner John P. Sheehan	Art Unit 1742	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2006/0016515 A1	01-2006	Tomizawa et al.	148/101
*	B	US-2003/0019546 A1	01-2003	Kanekiyo et al.	148/105
*	C	US-2002/0112785 A1	08-2002	Sekine et al.	148/302
*	D	US-5,352,302 A	10-1994	Takagi et al.	148/101
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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